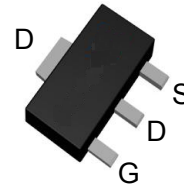




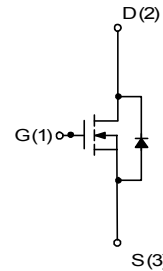
- 20V/30A
- $R_{DS(ON)}=4.6m\Omega$  (typ) @VGS=4.5V  
 $R_{DS(ON)}=5.8m\Omega$  (typ) @VGS=2.5V
- 100% UIS & RG Tested
- Reliable and Rugged
- Lead Free and Green Devices Available (RoHS Compliant)



Top View SOT-89

### Applications

- Power Management for Industrial DC/DC Converters



N-Channel MOSFET

### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Maximum	Units		
$V_{DS}$	Drain-Source Voltage	20	V		
$V_{GS}$	Gate-Source Voltage	$\pm 12$	V		
$I_D$	Continuous Drain Current	$T_A=25^\circ\text{C}$	30		
		$T_A=70^\circ\text{C}$	24		
$I_{DM}$	Pulsed Drain Current <sup>C</sup>	140	A		
$I_{AS}, I_{AR}$	Avalanche Current <sup>C</sup>	57	A		
$E_{AS}, E_{AR}$	Avalanche energy $L=0.1\text{mH}$ <sup>C</sup>	162	mJ		
$P_D$	Power Dissipation <sup>B</sup>	$T_A=25^\circ\text{C}$	3.1		
		$T_A=70^\circ\text{C}$	2		
Junction and Storage Temperature Range		-55 to 150	$^\circ\text{C}$		
Thermal Characteristics					
Symbol	Parameter	Typ	Max	Units	
$R_{\theta JA}$	Maximum Junction-to-Ambient <sup>A</sup>	$t \leq 10\text{s}$	31	40	$^\circ\text{C/W}$
	Maximum Junction-to-Ambient <sup>A D</sup>	Steady-State	59	75	$^\circ\text{C/W}$
$R_{\theta JL}$	Maximum Junction-to-Lead	Steady-State	60	90	$^\circ\text{C/W}$

**Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V	20			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =20V, V <sub>GS</sub> =0V T <sub>J</sub> =55°C			1 5	μA
I <sub>GSS</sub>	Gate-Body leakage current	V <sub>DS</sub> =0V, V <sub>GS</sub> = ±12V			100	nA
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	0.5	1	1.6	V
I <sub>D(ON)</sub>	On state drain current	V <sub>GS</sub> =10V, V <sub>DS</sub> =5V	140			A
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =4.5V, I <sub>D</sub> =20A T <sub>J</sub> =125°C		4.6	5.5	mΩ
		V <sub>GS</sub> =2.5V, I <sub>D</sub> =18A		5.5	7	
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> =5V, I <sub>D</sub> =20A		105		S
V <sub>SD</sub>	Diode Forward Voltage	I <sub>S</sub> =1A, V <sub>GS</sub> =0V		0.6	1	V
I <sub>S</sub>	Maximum Body-Diode Continuous Current				4	A
<b>DYNAMIC PARAMETERS</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =10V, f=1MHz	3080	3860	4630	pF
C <sub>oss</sub>	Output Capacitance		520	740	960	pF
C <sub>riss</sub>	Reverse Transfer Capacitance		350	580	810	pF
R <sub>g</sub>	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz	0.6	1.4	2.1	Ω
<b>SWITCHING PARAMETERS</b>						
Q <sub>g(4.5V)</sub>	Total Gate Charge	V <sub>GS</sub> =10V, V <sub>DS</sub> =10V, I <sub>D</sub> =20A	28	36	43	nC
Q <sub>gs</sub>	Gate Source Charge		7	9	11	nC
Q <sub>gd</sub>	Gate Drain Charge		7	12	17	nC
t <sub>D(on)</sub>	Turn-On DelayTime	V <sub>GS</sub> =10V, V <sub>DS</sub> =10V, R <sub>L</sub> =0.5Ω, R <sub>GEN</sub> =3Ω		7		ns
t <sub>r</sub>	Turn-On Rise Time			8		ns
t <sub>D(off)</sub>	Turn-Off DelayTime			70		ns
t <sub>f</sub>	Turn-Off Fall Time			18		ns
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =20A, dI/dt=500A/μs	13	17	20	ns
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	I <sub>F</sub> =20A, dI/dt=500A/μs	29	36	43	nC

A. The value of R<sub>θJA</sub> is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub> =25°C. The value in any given application depends on the user's specific board design.

B. The power dissipation P<sub>D</sub> is based on T<sub>J(MAX)</sub>=150°C, using ≤ 10s junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature T<sub>J(MAX)</sub>=150°C. Ratings are based on low frequency and duty cycles to keep initial T<sub>J</sub>=25°C. Maximum avalanche current limited by tester capability.

D. The R<sub>θJA</sub> is the sum of the thermal impedance from junction to lead R<sub>θJL</sub> and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, assuming a maximum junction temperature of T<sub>J(MAX)</sub>=150°C. The SOA curve provides a single pulse rating.

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### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

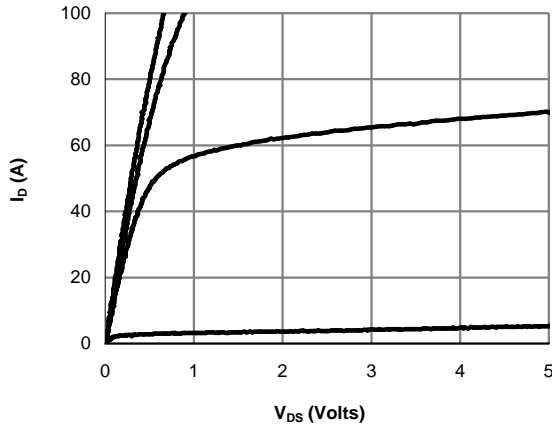


Figure 1: On-Region Characteristics (Note E)

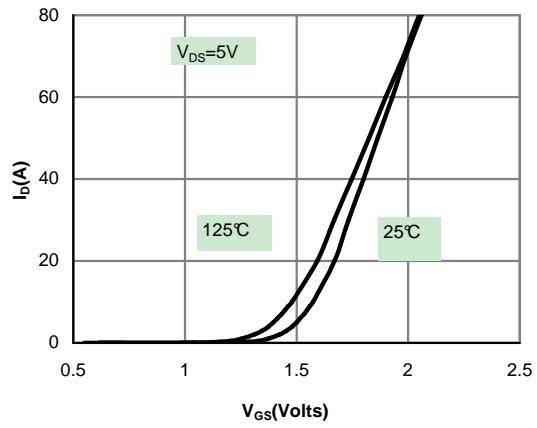


Figure 2: Transfer Characteristics (Note E)

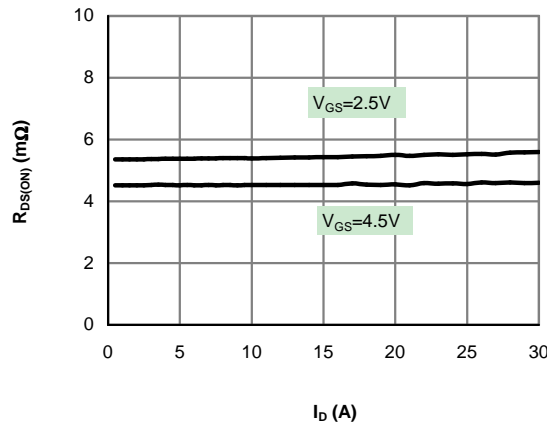


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

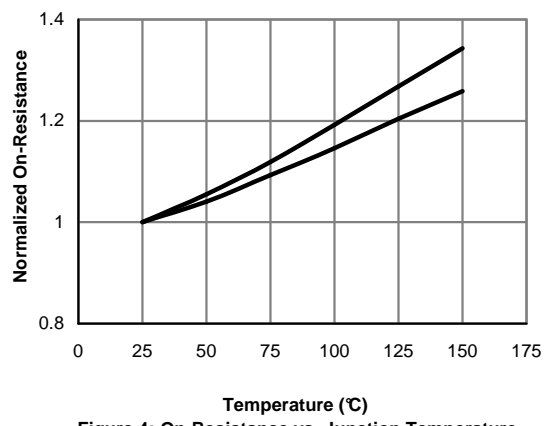


Figure 4: On-Resistance vs. Junction Temperature (Note E)

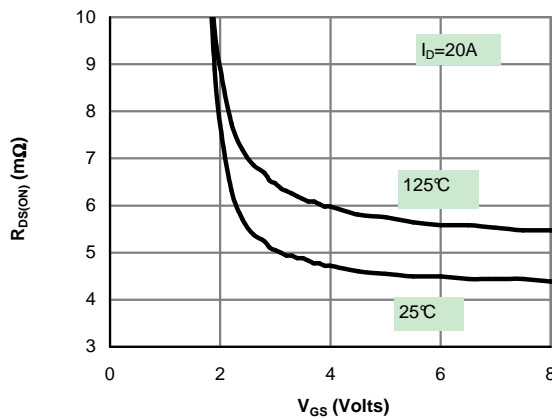


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

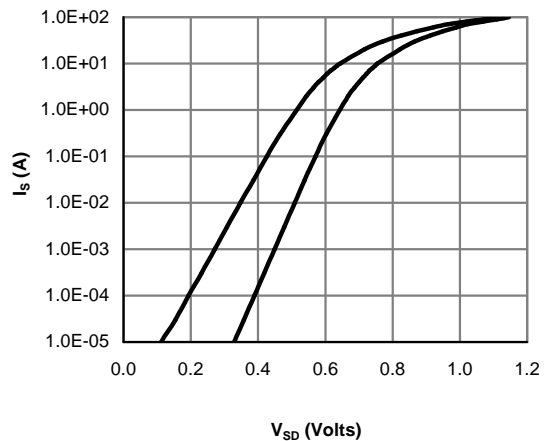


Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

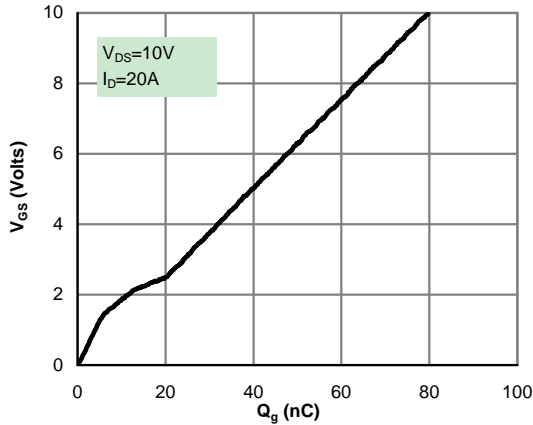


Figure 7: Gate-Charge Characteristics

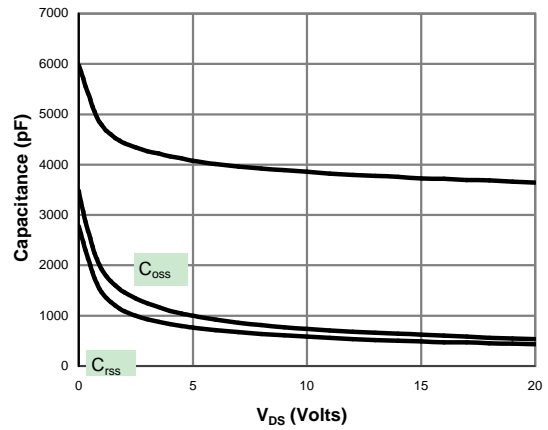


Figure 8: Capacitance Characteristics

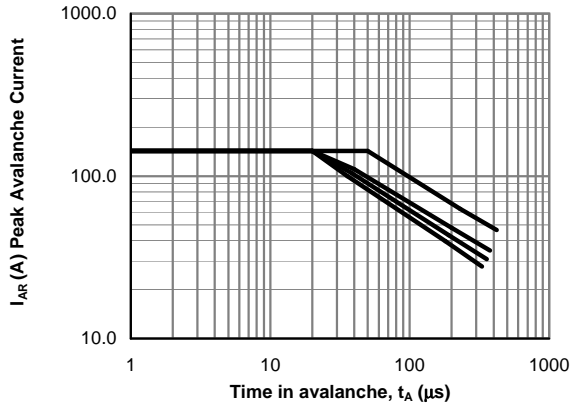


Figure 9: Single Pulse Avalanche capability (Note C)

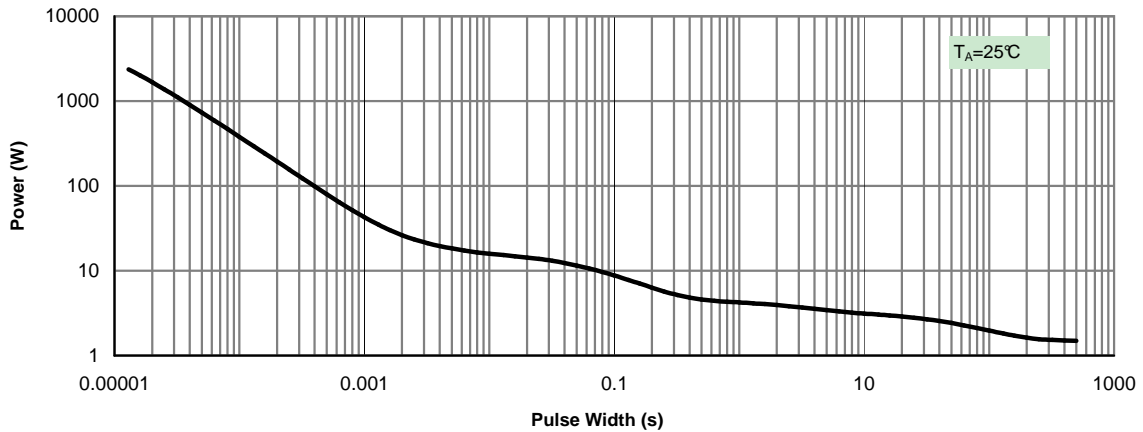
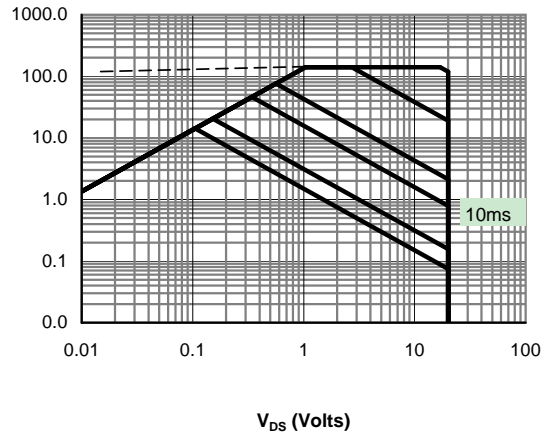


Figure 11: Single Pulse Power Rating Junction-to-Ambient (Note F)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

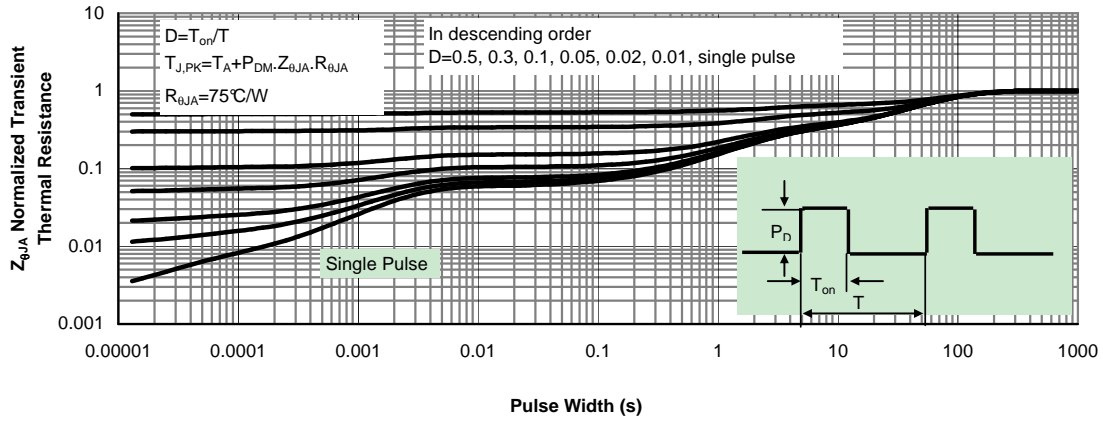
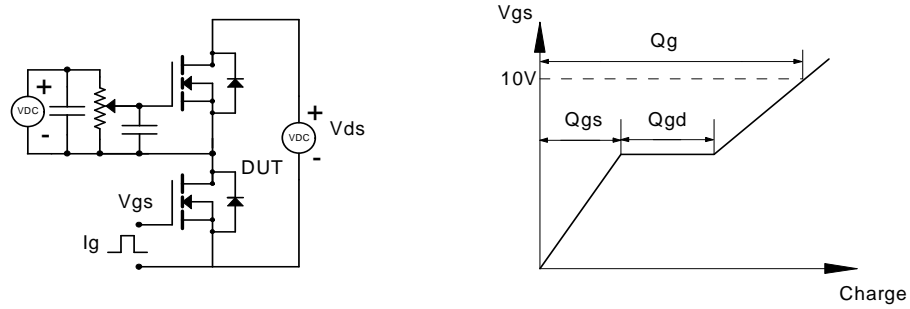
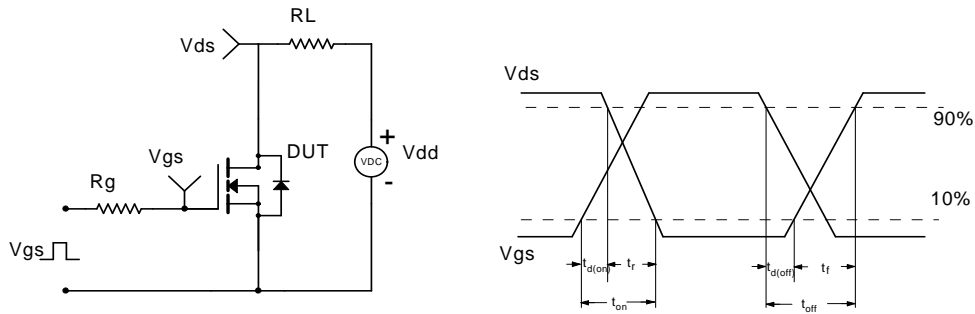


Figure 12: Normalized Maximum Transient Thermal Impedance (Note F)

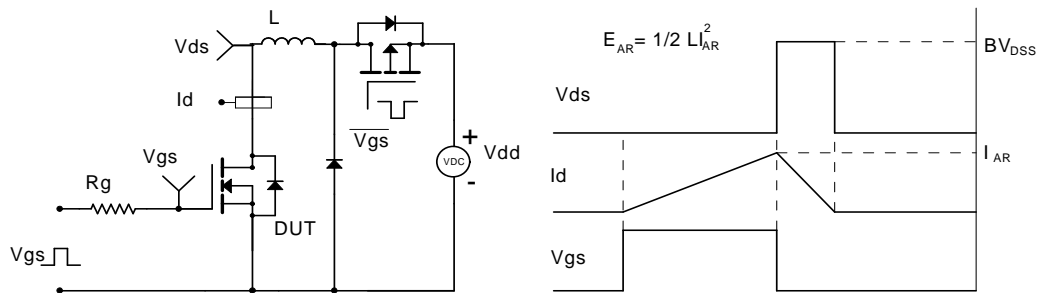
### Gate Charge Test Circuit & Waveform



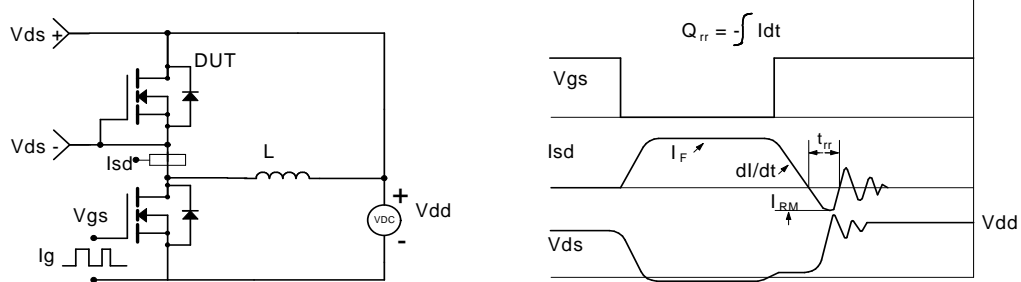
### Resistive Switching Test Circuit & Waveforms



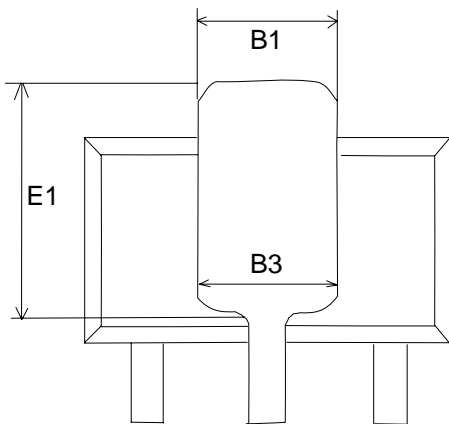
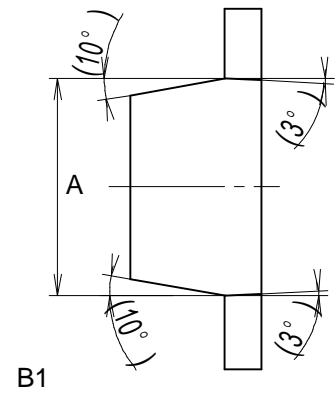
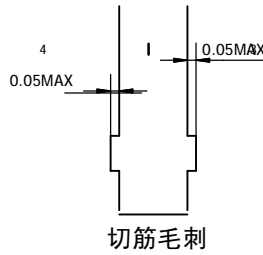
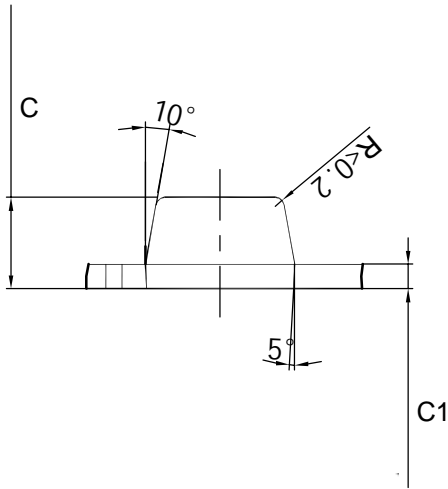
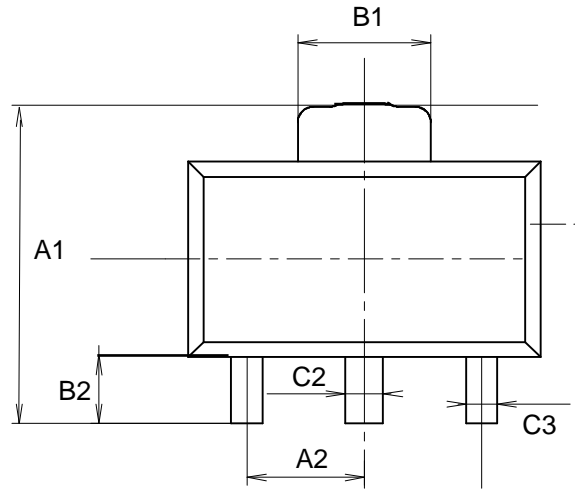
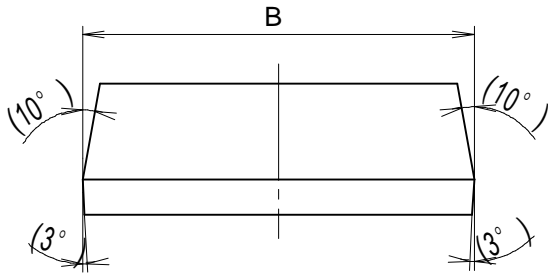
### Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



### Diode Recovery Test Circuit & Waveforms



SOT89-3L



COMMON DIMENSIONS			
UNITS MEASURE= MILLIMETER			
SYMBOL	MIN	NOM	MAX
A	2.35	2.45	2.55
A1	4.00	4.10	4.20
A2	1.45	1.50	1.55
B	4.40	4.50	4.60
B1		1.55 REF	
B2	1.00	1.10	1.20
B3		1.63 REF	
C	1.45	1.50	1.55
C1	0.39	0.40	0.41
C2	0.4	0.48	0.55
C3	0.35	0.4	0.45
E1	2.65	2.75	2.85